Notice of References Cited

Application/Control No.

10/699,214

Examiner

Mark S. Graham

Applicant(s)/Patent Under
Reexamination
LAI, SHU-MU

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,089,571	07-2000	Cho, Kunlin	273/371
	В	US-5,560,617	10-1996	Liang, Tu-Hsien	273/376
	С	US-6,394,458	05-2002	Chang, Wen-Fang	273/376
	D	US-6,116,607	09-2000	Cho, Kun Lin	273/371
	E	US-6,047,968	04-2000	Lu et al.	273/371
	F	US-5,788,244	08-1998	Hui et al.	273/374
	G	US-5,648,752	07-1997	Alfrey, Kip R.	340/323R
	Н	US-2002/0163131 A1	11-2002	Yiu, Chih-Hao	273/374
	1	US-6,659,465	12-2003	Yiu, Chin-Hao	273/374
	J	US-2002/0171203 A1	11-2002	Cho, Yu Fu	273/374
	K	US-2002/0063390 A1	05-2002	Cho, Yu-Fu	273/408
	L	US-2003/0214098 A1	11-2003	Chang, Wen-Fang	273/408
	М	US-4,561,660	12-1985	Zammuto, Samuel N.	273/376

FOREIGN PATENT DOCUMENTS

*	8	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				-	
	R				****	
	S					
	Т					

NON-PATENT DOCUMENTS

		
*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.